



# M8212

## 8-BIT INPUT/OUTPUT PORT

### MILITARY

- Fully Parallel 8-Bit Data Register and Buffer
- Service Request Flip-Flop for Interrupt Generation
- Low Input Load Current 0.25mA Max
- 3-State Outputs
- Military Temperature Range  
-55° C to +125° C
- 3.4V Output High Voltage for Direct Interface to M8080A CPU
- Asynchronous Register Clear
- Replaces Buffers, Latches, and Multiplexers in Microcomputer Systems
- Reduces System Package Count
- ±10% Power Supply Tolerance
- 24-Pin Dual In-Line Package

The Intel® M8212/M3212 input/output port consists of an 8-bit latch with 3-state output buffers along with control and device selection logic. Also included is a service request flip-flop for the generation and control of interrupts to the microprocessor.

The device is multimode in nature. It can be used to implement latches, gated buffers or multiplexers. Thus, all of the principal peripheral and input/output functions of a microcomputer system can be implemented with this device.

\*Note: The specifications for the M3212 are identical with those for the M8212.

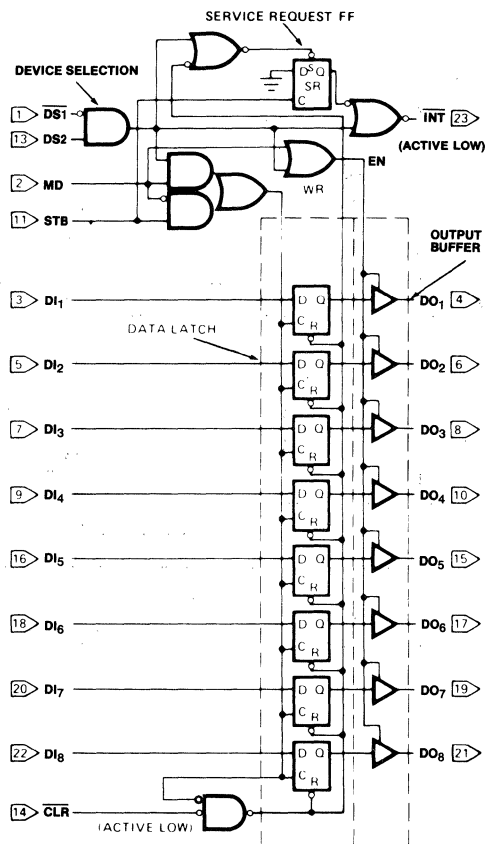
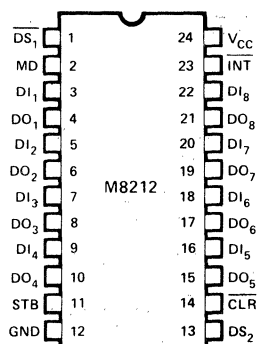


Figure 1. Logic Diagram



DI <sub>1</sub> , DI <sub>8</sub>	DATA IN
DO <sub>1</sub> , DO <sub>8</sub>	DATA OUT
DS <sub>1</sub> , DS <sub>2</sub>	DEVICE SELECT
MD	MODE
STB	STROBE
INT	INTERRUPT (ACTIVE LOW)
CLR	CLEAR (ACTIVE LOW)

Figure 2. Pin Configuration

**ABSOLUTE MAXIMUM RATINGS\***

Temperature Under Bias .....  $-55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$   
 Storage Temperature .....  $-65^{\circ}\text{C}$  to  $+160^{\circ}\text{C}$   
 All Output or Supply Voltages ....  $-0.5$  to  $+7$  Volts  
 All Input Voltages .....  $-1.0$  to  $5.5$  Volts  
 Output Currents .....  $100$  mA

*\*NOTICE: Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.*

**D.C. CHARACTERISTICS** ( $T_A = -55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ ,  $V_{CC} = +5\text{V} \pm 10\%$ )

Symbol	Parameter	Limits			Unit	Test Conditions
		Min.	Typ.	Max.		
$I_F$	Input Load Current STB, DS <sub>2</sub> , CR, DI <sub>1</sub> -DI <sub>8</sub> Inputs			-.25	mA	$V_F = .45\text{V}$
$I_F$	Input Load Current MD Input			-.75	mA	$V_F = .45\text{V}$
$I_F$	Input Load Current DS <sub>1</sub> Input			-1.0	mA	$V_F = .45\text{V}$
$I_R$	Input Leakage Current STB, DS, CR, DI <sub>1</sub> -DI <sub>8</sub> Inputs			10	$\mu\text{A}$	$V_R = V_{CC}$
$I_R$	Input Leakage Current MD Input			30	$\mu\text{A}$	$V_R = V_{CC}$
$I_R$	Input Leakage Current DS <sub>1</sub> Input			40	$\mu\text{A}$	$V_R = V_{CC}$
$V_C$	Input Forward Voltage Clamp			-1.2	V	$I_C = -5$ mA
$V_{IL}$	Input "Low" Voltage			.80	V	
$V_{IH}$	Input "High" Voltage	2.0			V	
$V_{OL}$	Output "Low" Voltage			.45	V	$I_{OL} = 10\text{mA}$
$V_{OH}$	Output "High" Voltage	3.5	4.0		V	$I_{OH} = -.5\text{mA}$
$I_{OS}$	Short Circuit Output Current	-15		-75	mA	$V_{CC} = 5.0\text{V}$
$ I_O $	Output Leakage Current High Impedance State			20	$\mu\text{A}$	$V_O = .45\text{V}$ to $V_{CC}$
$I_{CC}$	Power Supply Current		90	145	mA	

**CAPACITANCE** ( $F = 1$  MHz,  $V_{BIAS} = 2.5\text{V}$ ,  $V_{CC} = +5\text{V}$ ,  $T_A = 25^{\circ}\text{C}$ )

Symbol	Test	LIMITS	
		Typ.	Max.
$C_{IN}$	$\overline{DS}$ , MD Input Capacitance	9 pF	15 pF
$C_{IN}$	DS <sub>1</sub> , $\overline{CLR}$ , STB <sub>1</sub> , DI <sub>1</sub> -DI <sub>8</sub> Input Capacitance	5 pF	10 pF
$C_{OUT}$	DO -DO <sub>8</sub> Output Capacitance	8 pF	15 pF

**Conditions of Test**

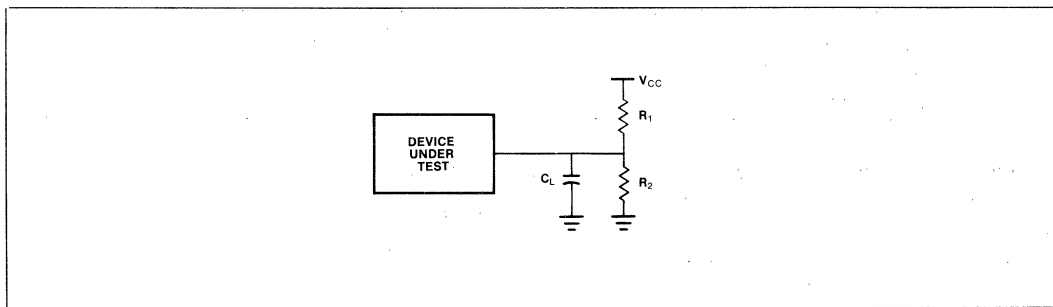
Input Pulse Amplitude = 2.5V  
 Input Rise and Fall Times: 5 ns between 1V and 2V  
 Measurements made at 1.5V

**A.C. CHARACTERISTICS** ( $T_A = -55^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ ,  $V_{CC} = +5\text{V} \pm 10\%$ )

Symbol	Parameter	Limits		Unit	Test Conditions
		Min.	Max.		
$t_{PW}$	Pulse Width	40		ns	
$t_{PD}$	Data To Output Delay		30	ns	NOTE 1
$t_{WE}$	Write Enable To Output Delay		50	ns	NOTE 1
$t_{SET}$	Data Setup Time	20		ns	
$t_H$	Data Hold Time	30		ns	
$t_R$	Reset To Output Delay		55	ns	NOTE 1
$t_S$	Set To Output Delay		35	ns	NOTE 1
$t_E$	Output Enable/Disable Time		50	ns	NOTE 1 $C_L = 30\text{ pF}$
$t_C$	Clear To Output Delay		55	ns	NOTE 1

**NOTE 1:**

TEST	$C_L$	$R_1$	$R_2$
$t_{PD}$ , $t_{WE}$ , $t_R$ , $t_S$ , $t_C$	30pF	300 $\Omega$	600 $\Omega$
$t_E$ , ENABLE $\uparrow$	30pF	10K $\Omega$	1K $\Omega$
$t_E$ , ENABLE $\downarrow$	30pF	300 $\Omega$	600 $\Omega$
$t_E$ , DISABLE $\uparrow$	5pF	300 $\Omega$	600 $\Omega$
$t_E$ , DISABLE $\downarrow$	5pF	10K $\Omega$	1K $\Omega$

**A.C. TESTING LOAD CIRCUIT**


WAVEFORMS

